

2:4 Low Additive Jitter LVDS Buffer

Check for Samples: [CDCLVD1204](#)

FEATURES

- 2:4 Differential Buffer
- Low Additive Jitter: <300 fs RMS in 10-kHz to 20-MHz
- Low Output Skew of 20 ps (Max)
- Universal Inputs Accept LVDS, LVPECL, and LVC MOS
- Selectable Clock Inputs through Control Pin
- 4 LVDS Outputs, ANSI EAI/TIA-644A Standard Compatible
- Clock Frequency up to 800 MHz
- 2.375 V–2.625 V Device Power Supply
- LVDS Reference Voltage, V_{AC_REF} , Available for Capacitive Coupled Inputs
- Industrial Temperature Range: –40°C to 85°C
- Packaged in 3 mm × 3 mm 16-Pin QFN (RGT)
- ESD Protection Exceeds 3 kV HBM, 1 kV CDM

APPLICATIONS

- Telecommunications/Networking
- Medical Imaging
- Test and Measurement Equipment
- Wireless Communications
- General Purpose Clocking

DESCRIPTION

The CDCLVD1204 clock buffer distributes one of two selectable clock inputs, (IN0, IN1), to 4 pairs of differential LVDS clock outputs (OUT0, OUT3) with minimum skew for clock distribution. The CDCLVD1204 can accept two clock sources into an input multiplexer. The inputs can either be LVDS, LVPECL, or LVC MOS.

The CDCLVD1204 is specifically designed for driving 50 Ω transmission lines. In case of driving the inputs in single ended mode, the appropriate bias voltage (V_{AC_REF}) should be applied to the unused negative input pin.

The IN_SEL pin selects the input which is routed to the outputs. If this pin is left open it disables the outputs (static). The part supports a fail safe function. The device incorporates an input hysteresis which prevents random oscillation of the outputs in the absence of an input signal.

The device operates in 2.5V supply environment and is characterized from –40°C to 85°C (ambient temperature). The CDCLVD1204 is packaged in small 16-pin, 3-mm × 3-mm QFN package.

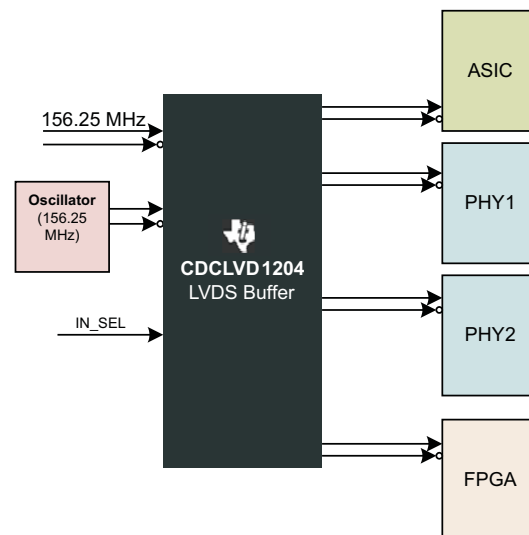


Figure 1. Application Example



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

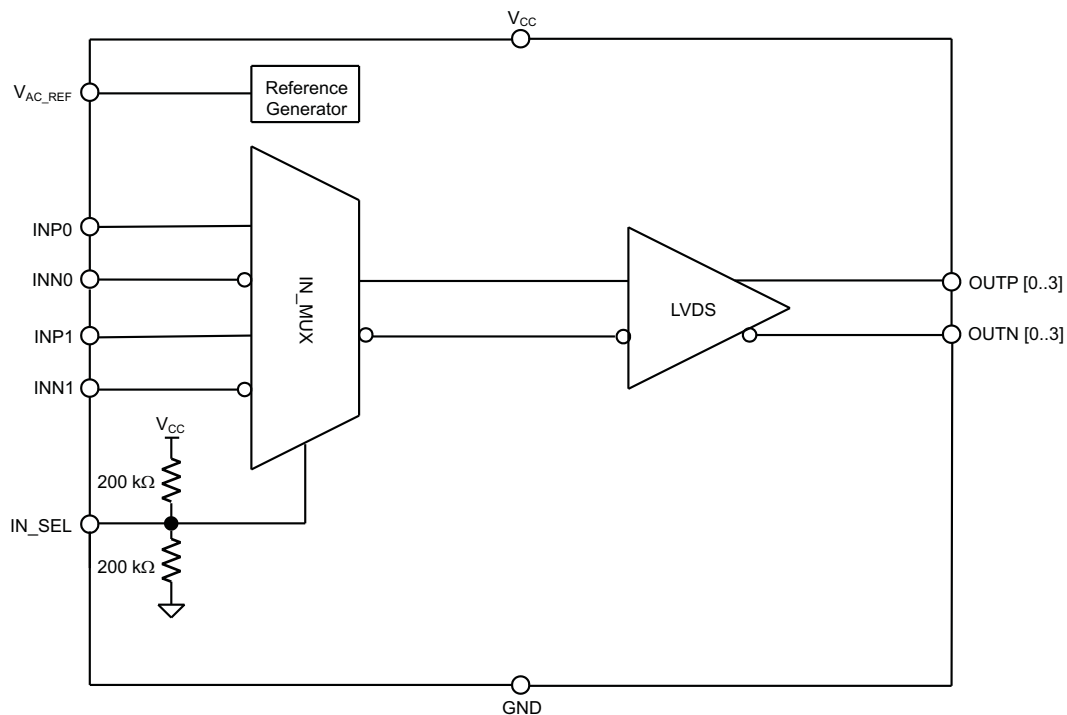
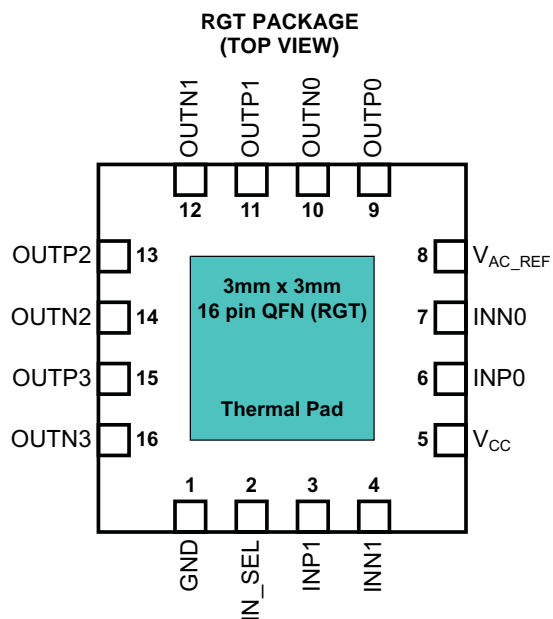


Figure 2. CDCLVD1204 Block Diagram



PIN DESCRIPTIONS

CDCLVD1204 Pin Descriptions

PIN		TYPE	DESCRIPTION
NAME	NO.		
V _{CC}	5	Power	2.5 V supply for the device
GND	1	Ground	Device ground
INP0, INN0	6, 7	Input	Differential input pair or single ended input
INP1, INN1	3, 4	Input	Differential redundant input pair or single ended input
V _{AC_REF}	8	Output	Bias voltage output for capacitive coupled inputs. If used, it is recommended to use a 0.1µF to GND on this pin.
OUTP0, OUTN0	9, 10	Output	Differential LVDS output pair No. 0
OUTP1, OUTN1	11,12	Output	Differential LVDS output pair No. 1
OUTP2, OUTN2	13,14	Output	Differential LVDS output pair No. 2
OUTP3, OUTN3	15,16	Output	Differential LVDS output pair No. 3
IN_SEL	2	Input with an internal 200kΩ pull-up and pull-down	Input selection – selects input port; (See Table 1)
Thermal Pad			See thermal management recommendations

Table 1. Input Selection

IN_SEL	ACTIVE CLOCK INPUT
0	INP0, INN0
1	INP1, INN1
Open	None ⁽¹⁾

(1) The input buffers are disabled and the outputs are static.

ABSOLUTE MAXIMUM RATINGS

Over operating free-air temperature range (unless otherwise noted).⁽¹⁾

	VALUE	UNIT
Supply voltage range, V _{CC}	–0.3 to 2.8	V
Input voltage range, V _I	–0.2 to V _{CC} +0.2	V
Output voltage range, V _O	–0.2 to V _{CC} +0.2	V
Driver short circuit current, I _{OSD}	See Note ⁽²⁾	
Electrostatic discharge (Human Body Model, 1.5 kΩ, 100 pF)	>3000	V

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The output can handle the permanent short.

RECOMMENDED OPERATING CONDITIONS

Over operating free-air temperature range (unless otherwise noted).

	MIN	TYP	MAX	UNIT
Device supply voltage, V _{CC}	2.375	2.5	2.625	V
Ambient temperature, T _A	–40		85	°C

THERMAL INFORMATION

THERMAL METRIC ⁽¹⁾		CDCLVD1204	UNITS
		RGT	
		16 PINS	
θ_{JA}	Junction-to-ambient thermal resistance	51.3	°C/W
$\theta_{JC(top)}$	Junction-to-case(top) thermal resistance	85.4	
θ_{JB}	Junction-to-board thermal resistance	20.1	
ψ_{JT}	Junction-to-top characterization parameter	1.3	
ψ_{JB}	Junction-to-board characterization parameter	19.4	
$\theta_{JC(bottom)}$	Junction-to-case(bottom) thermal resistance	6	

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, [SPRA953](#).

ELECTRICAL CHARACTERISTICS

At $V_{CC} = 2.375\text{ V}$ to 2.625 V and $T_A = -40^\circ\text{C}$ to 85°C (unless otherwise noted).

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
IN_SEL CONTROL CHARACTERISTICS						
Vd _{I3}	3-State	Open	0.5×V _{CC}			V
Vd _{IH}	Input high voltage		0.7×V _{CC}			V
Vd _{IL}	Input low voltage		0.2×V _{CC}			V
Id _{IH}	Input high current	V _{CC} = 2.625 V, V _{IH} = 2.625 V		30		μA
Id _{IL}	Input low current	V _{CC} = 2.625 V, V _{IL} = 0 V		–30		μA
R _{pull(IN_SEL)}	Input pull-up/ pull-down resistor		200			kΩ
2.5V LVCMOS (see Figure 7) INPUT CHARACTERISTICS						
f _{IN}	Input frequency			200		MHz
V _{th}	Input threshold voltage	External threshold voltage applied to complementary input	1.1		1.5	V
V _{IH}	Input high voltage		V _{th} + 0.1		V _{CC}	V
V _{IL}	Input low voltage		0		V _{th} – 0.1	V
I _{IH}	Input high current	V _{CC} = 2.625 V, V _{IH} = 2.625 V		10		μA
I _{IL}	Input low current	V _{CC} = 2.625 V, V _{IL} = 0 V		–10		μA
ΔV/ΔT	Input edge rate	20% – 80%	1.5			V/ns
C _{IN}	Input capacitance		2.5			pF
DIFFERENTIAL INPUT CHARACTERISTICS						
f _{IN}	Input frequency	Clock input			800	MHz
V _{IN, DIFF}	Differential input voltage peak-to-peak	V _{ICM} = 1.25 V	0.3		1.6	V _{PP}
V _{ICM}	Input common-mode voltage range	V _{IN, DIFF, PP} > 0.4V	1		V _{CC} – 0.3	V
I _{IH}	Input high current	V _{CC} = 2.625 V, V _{IH} = 2.625 V		10		μA
I _{IL}	Input low current	V _{CC} = 2.625 V, V _{IL} = 0 V		–10		μA
ΔV/ΔT	Input edge rate	20% to 80%	0.75			V/ns
C _{IN}	Input capacitance		2.5			pF

ELECTRICAL CHARACTERISTICS (continued)

At $V_{CC} = 2.375\text{ V}$ to 2.625 V and $T_A = -40^\circ\text{C}$ to 85°C (unless otherwise noted).

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
LVDS OUTPUT CHARACTERISTICS						
$ V_{OD} $	Differential output voltage magnitude	$V_{IN, DIFF, PP} = 0.3\text{ V}, R_L = 100\ \Omega$	250		450	mV
ΔV_{OD}	Change in differential output voltage magnitude		–15		15	mV
$V_{OC(SS)}$	Steady-state common mode output voltage		1.1		1.375	V
$\Delta V_{OC(SS)}$	Steady-state common mode output voltage	$V_{IN, DIFF, PP} = 0.6\text{ V}, R_L = 100\ \Omega$	–15		15	mV
V_{ring}	Output overshoot and undershoot	Percentage of output amplitude V_{OD}			10%	
V_{OS}	Output ac common mode	$V_{IN, DIFF, PP} = 0.6\text{ V}, R_L = 100\ \Omega$		25	70	mV _{PP}
I_{OS}	Short-circuit output current	$V_{OD} = 0\text{ V}$			±24	mA
t_{PD}	Propagation delay	$V_{IN, DIFF, PP} = 0.3\text{ V}$		1.5	2.5	ns
$t_{SK, PP}$	Part-to-part skew				600	ps
$t_{SK, O}$	Output skew				20	ps
$t_{SK, P}$	Pulse skew(with 50% duty cycle input)	Crossing-point-to-crossing-point distortion	–50		50	ps
t_{RJIT}	Random additive jitter (with 50% duty cycle input)	Edge speed = 0.75V/ns 10 kHz – 20 MHz			0.3	ps, RMS
t_R/t_F	Output rise/fall time	20% to 80%, 100 Ω , 5 pF	50		300	ps
I_{CCSTAT}	Static supply current	Outputs unterminated, $f = 0\text{ Hz}$		17	28	mA
I_{CC100}	Supply current	All outputs, $R_L = 100\ \Omega$, $f = 100\text{ MHz}$		40	58	mA
I_{CC800}	Supply current	All outputs, $R_L = 100\ \Omega$, $f = 800\text{ MHz}$		60	80	mA
$V_{AC, REF}$ CHARACTERISTICS						
$V_{AC, REF}$	Reference output voltage	$V_{CC} = 2.5\text{ V}, I_{load} = 100\ \mu\text{A}$	1.1	1.25	1.35	V

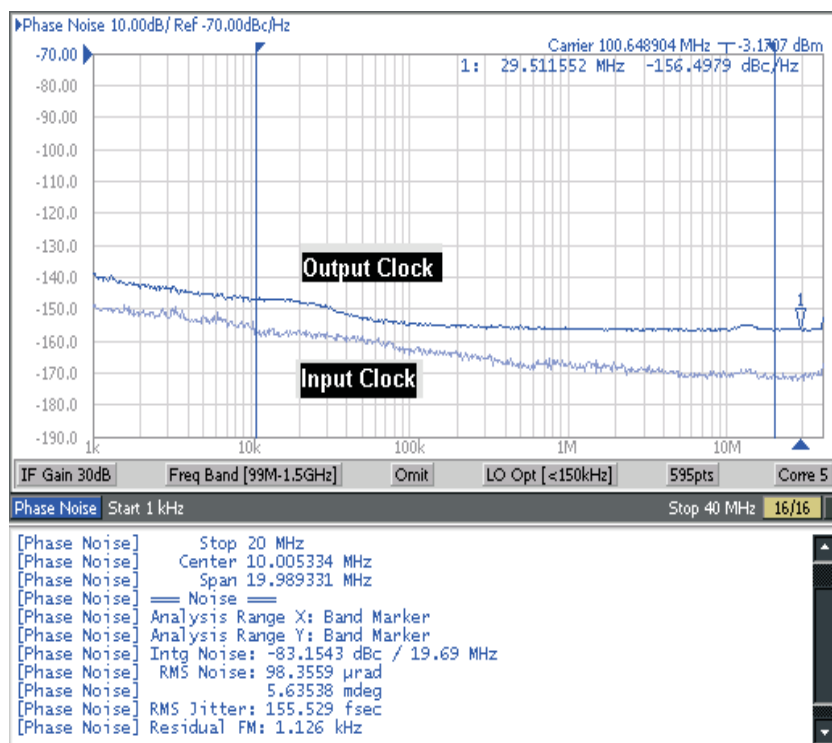
Typical Additive Phase Noise Characteristics for 100 MHz Clock

PARAMETER		MIN	TYP	MAX	UNIT
phn ₁₀₀	Phase noise at 100 Hz offset		-132.9		dBc/Hz
phn _{1k}	Phase noise at 1 kHz offset		-138.8		dBc/Hz
phn _{10k}	Phase noise at 10 kHz offset		-147.4		dBc/Hz
phn _{100k}	Phase noise at 100 kHz offset		-153.6		dBc/Hz
phn _{1M}	Phase noise at 1 MHz offset		-155.2		dBc/Hz
phn _{10M}	Phase noise at 10 MHz offset		-156.2		dBc/Hz
phn _{20M}	Phase noise at 20 MHz offset		-156.6		dBc/Hz
t _{RJIT}	Random additive jitter from 10 kHz to 20 MHz		171		fs, RMS

Typical Additive Phase Noise Characteristics for 737.27 MHz Clock

PARAMETER		MIN	TYP	MAX	UNIT
phn ₁₀₀	Phase noise at 100 Hz offset		-80.2		dBc/Hz
phn _{1k}	Phase noise at 1 kHz offset		-114.3		dBc/Hz
phn _{10k}	Phase noise at 10 kHz offset		-138		dBc/Hz
phn _{100k}	Phase noise at 100 kHz offset		-143.9		dBc/Hz
phn _{1M}	Phase noise at 1 MHz offset		-145.2		dBc/Hz
phn _{10M}	Phase noise at 10 MHz offset		-146.5		dBc/Hz
phn _{20M}	Phase noise at 20 MHz offset		-146.6		dBc/Hz
t _{RJIT}	Random additive jitter from 10 kHz to 20 MHz		65		fs, RMS

TYPICAL CHARACTERISTICS **INPUT CLOCK AND OUTPUT CLOCK PHASE NOISES** **vs** **FREQUENCY FROM THE CARRIER ($T_A = 25^\circ\text{C}$ and $V_{CC} = 2.5\text{V}$)**



Input clock RMS jitter is 32 fs from 10 kHz to 20 MHz and additive RMS jitter is 152 fs

Figure 3. 100 MHz Input and Output Phase Noise Plot

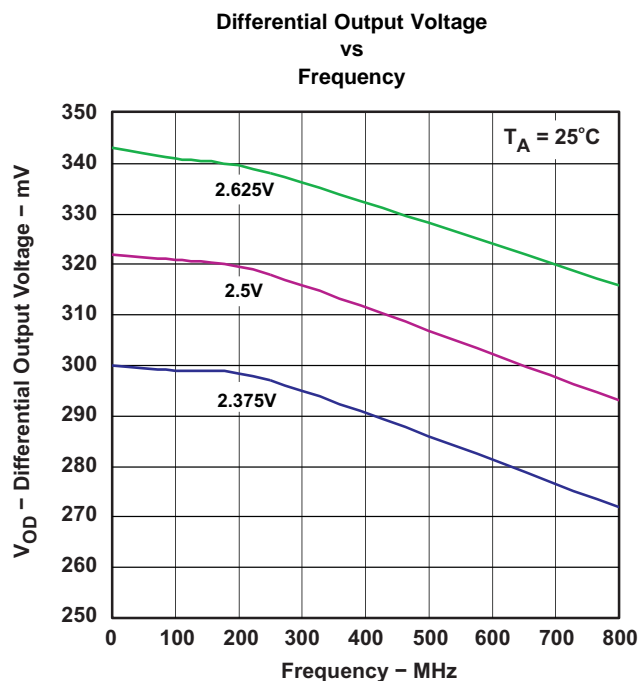


Figure 4.

TEST CONFIGURATIONS

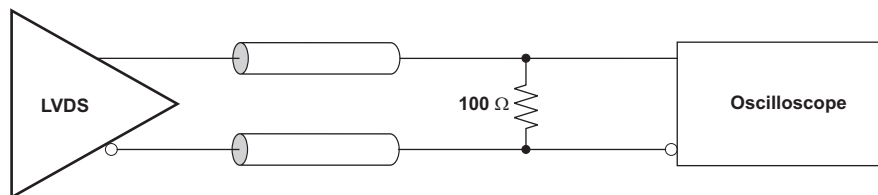


Figure 5. LVDS Output DC Configuration During Device Test

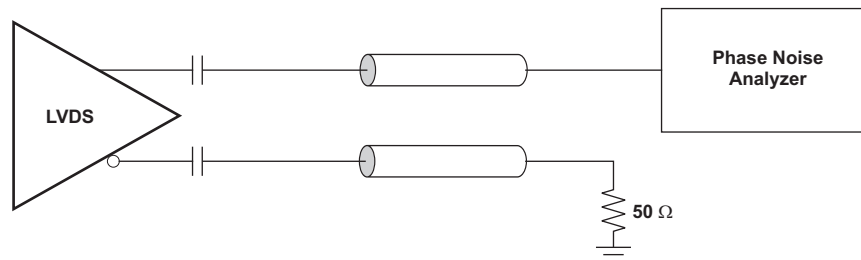


Figure 6. LVDS Output AC Configuration During Device Test

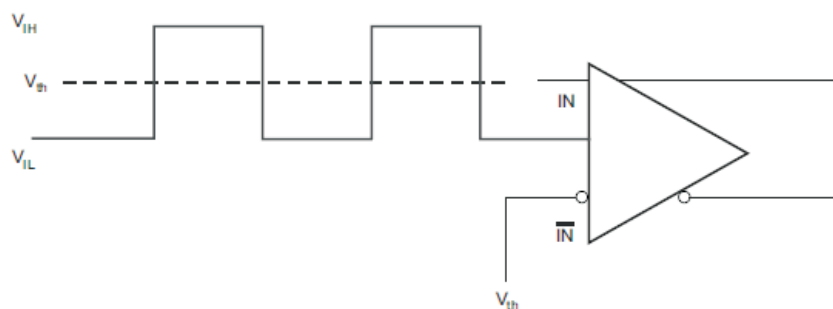


Figure 7. DC Coupled LVCMOS Input During Device Test

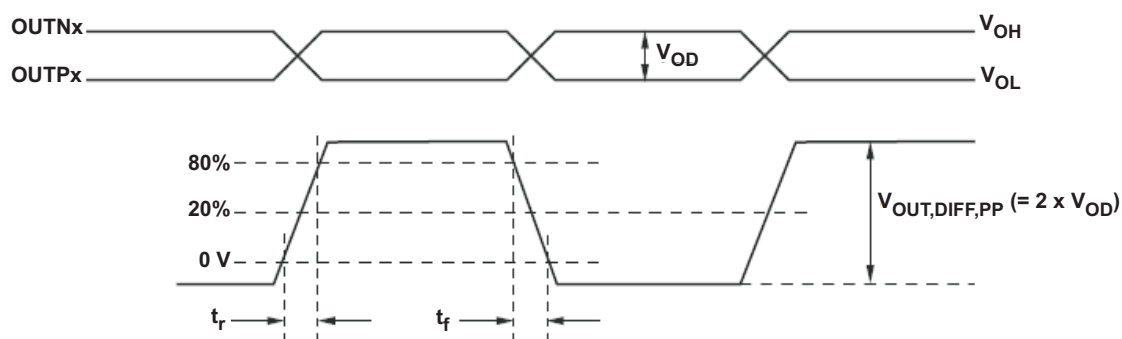
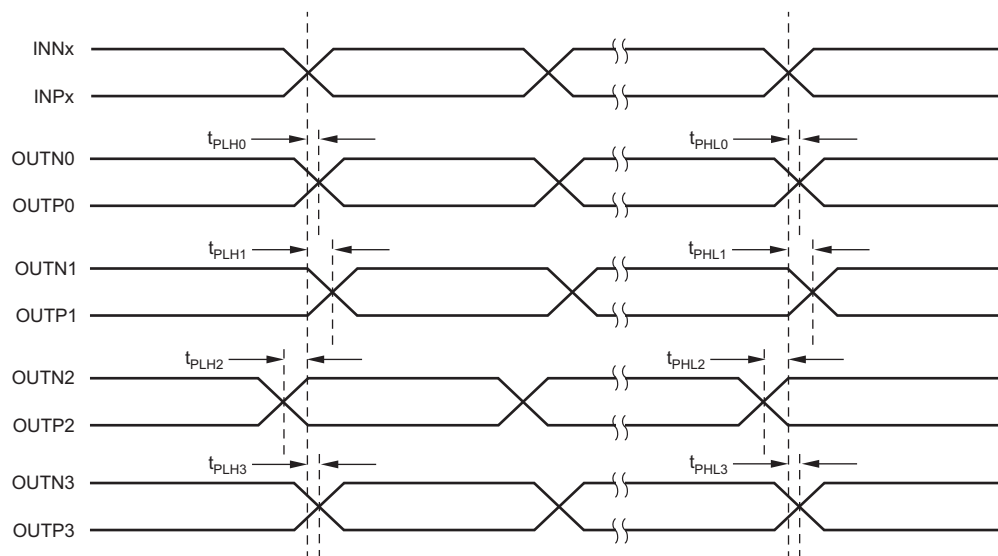


Figure 8. Output Voltage and Rise/Fall Time



- (1) Output skew is calculated as the greater of the following: As the difference between the fastest and the slowest t_{PLHn} or the difference between the fastest and the slowest t_{PHLn} ($n = 0, 1, 2, 3$).
- (2) Part-to-part skew is calculated as the greater of the following: As the difference between the fastest and the slowest t_{PLHn} or the difference between the fastest and the slowest t_{PHLn} across multiple devices ($n = 0, 1, 2, 3$).

Figure 9. Output Skew and Part-to-Part Skew

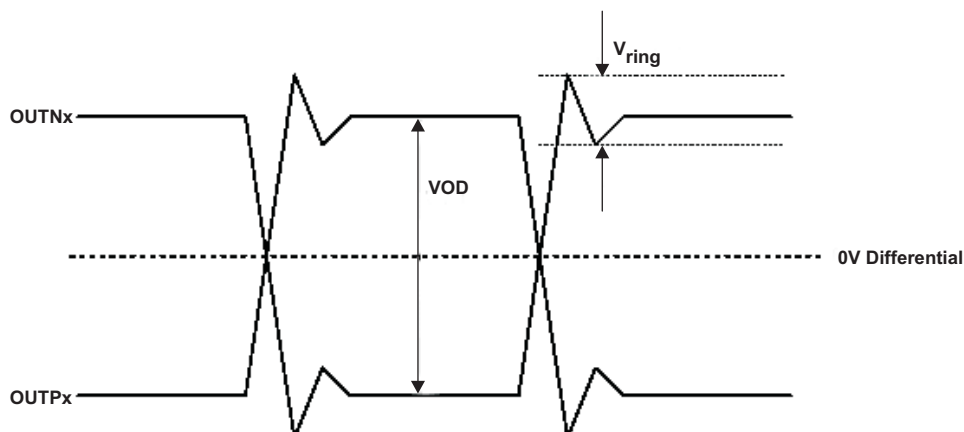


Figure 10. Output Overshoot and Undershoot

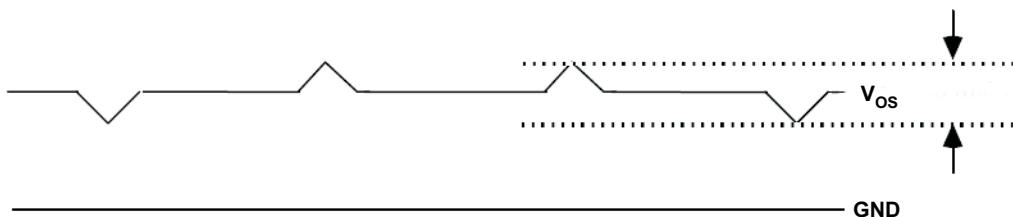


Figure 11. Output AC Common Mode

APPLICATION INFORMATION

THERMAL MANAGEMENT

For reliability and performance reasons, the die temperature should be limited to a maximum of 125°C.

The device package has an exposed pad that provides the primary heat removal path to the printed circuit board (PCB). To maximize the heat dissipation from the package, a thermal landing pattern including multiple vias to a ground plane must be incorporated into the PCB within the footprint of the package. The Thermal Pad must be soldered down to ensure adequate heat conduction to of the package. Figure 12 shows a recommended land and via pattern.

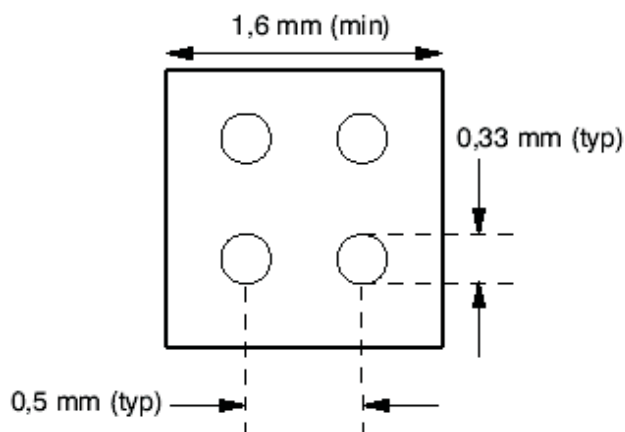


Figure 12. Recommended PCB Layout

POWER-SUPPLY FILTERING

High-performance clock buffers are sensitive to noise on the power supply, which can dramatically increase the additive jitter of the buffer. Thus, it is essential to reduce noise from the system power supply, especially when jitter/phase noise is critical to applications.

Filter capacitors are used to eliminate the low-frequency noise from the power supply, where the bypass capacitors provide the low impedance path for high-frequency noise and guard the power-supply system against the induced fluctuations. These bypass capacitors also provide instantaneous current surges as required by the device and should have low equivalent series resistance (ESR). To properly use the bypass capacitors, they must be placed close to the power-supply pins and laid out with short loops to minimize inductance. It is recommended to add as many high-frequency (for example, 0.1 μF) bypass capacitors as there are supply pins in the package. It is recommended, but not required, to insert a ferrite bead between the board power supply and the chip power supply that isolates the high-frequency switching noises generated by the clock driver; these beads prevent the switching noise from leaking into the board supply. Choose an appropriate ferrite bead with low dc resistance because it is imperative to provide adequate isolation between the board supply and the chip supply, as well as to maintain a voltage at the supply pins that is greater than the minimum voltage required for proper operation.

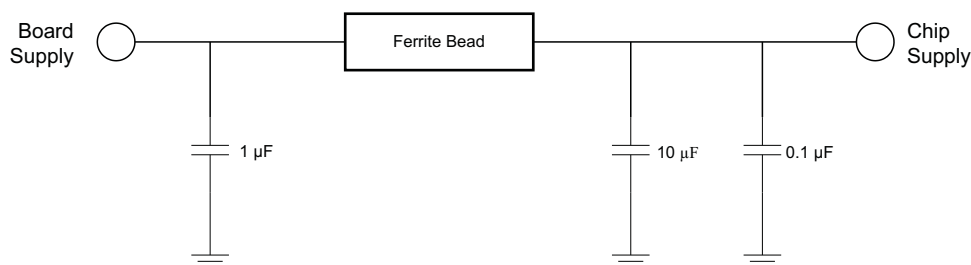


Figure 13. Power-Supply Decoupling

LVDS OUTPUT TERMINATION

The proper LVDS termination for signal integrity over two 50 Ω lines is 100 Ω between the outputs on the receiver end. Either dc-coupled termination or ac-coupled termination can be used for LVDS outputs. It is recommended to place termination resistor close to the receiver. If the receiver is internally biased to a voltage different than the output common mode voltage of the CDCLVD1204, ac-coupling should be used. If the LVDS receiver has internal 100 Ω termination, external termination must be omitted.

Unused outputs can be left open without connecting any trace to the output pins.

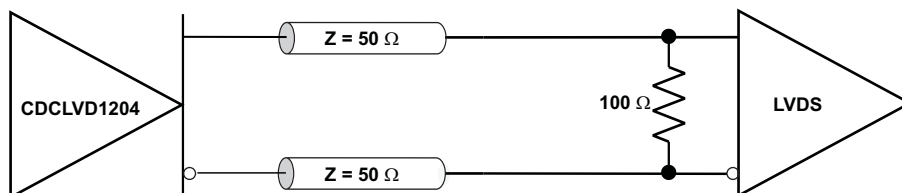


Figure 14. Output DC Termination

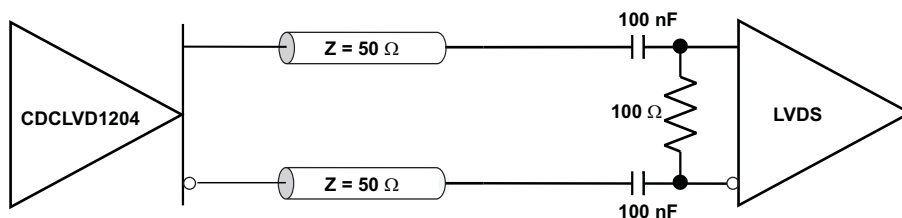


Figure 15. Output AC Termination (With the Receiver Internally Biased)

INPUT TERMINATION

The CDCLVD1204 inputs can be interfaced with LVDS, LVPECL, or LVCMOS drivers.

LVDS Driver can be connected to CDCLVD1204 inputs with dc or ac coupling as shown [Figure 16](#) and [Figure 17](#), respectively.

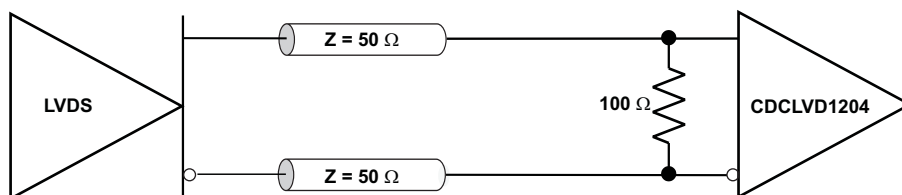


Figure 16. LVDS Clock Driver Connected to CDCLVD1204 Input (DC Coupled)

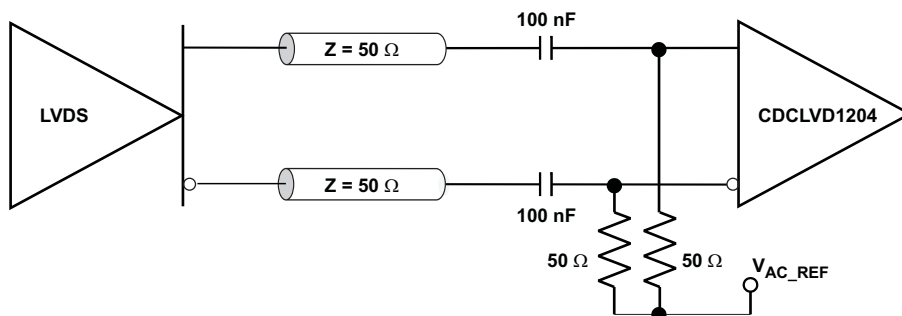


Figure 17. LVDS Clock Driver Connected to CDCLVD1204 Input (AC Coupled)

Figure 18 shows how to connect LVPECL inputs to the CDCLVD1204. The series resistors are required to reduce the LVPECL signal swing if the signal swing is >1.6 V_{pp}.

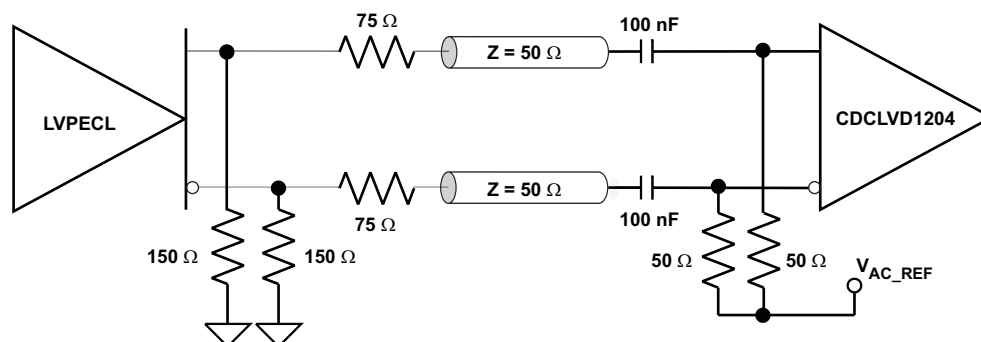


Figure 18. LVPECL Clock Driver Connected to CDCLVD1204 Input

Figure 19 illustrates how to couple a 2.5 V LVCMOS clock input to the CDCLVD1204 directly. The series resistance (R_S) should be placed close to the LVCMOS driver if needed. 3.3 V LVCMOS clock input swing needs to be limited to $V_{IH} \leq V_{CC}$.

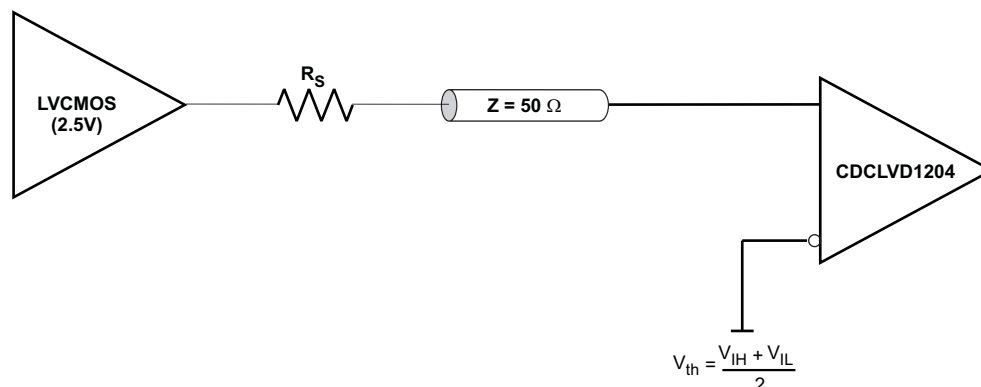


Figure 19. 2.5V LVCMOS Clock Driver Connected to CDCLVD1204 Input

For unused input, it is recommended to ground both the input pins (INP, INN) using 1 kΩ resistors.

REVISION HISTORY

Changes from Original (May 2010) to Revision A	Page
• Changed Features bullet - From: ESD Protection Exceeds 2 kV HBM, 500 V CDM To: ESD Protection Exceeds 3 kV HBM, 1 kV CDM	1
• Updated the V_{AC_REF} pin description	3
• Updated Table 1 - Input Selection	3
• Electrostatic discharge was >2000	3
• ΔV_{OD} values, MIN was -50, MAX was 50	5
• $V_{OC(SS)}$ MIN value was 1.125	5
• $\Delta V_{OC(SS)}$ values, MIN was -50, MAX was 50	5
• V_{ring} MAX value was 20%	5
• V_{OS} values, TYP was 30, MAX was 100	5
• t_{PD} MAX value was 2	5
• $t_{SK, PP}$ - deleted the TYP value of 300	5
• t_R/t_F MIN value was 200	5
• I_{CCSTAT} MAX value was 25	5

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp (3)	Op Temp (°C)	Top-Side Markings (4)	Samples
CDCLVD1204RGTR	ACTIVE	QFN	RGT	16	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	D1204	Samples
CDCLVD1204RGTT	ACTIVE	QFN	RGT	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	D1204	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

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TAPE AND REEL INFORMATION


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDCLVD1204RGTR	QFN	RGT	16	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
CDCLVD1204RGTT	QFN	RGT	16	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

TAPE AND REEL BOX DIMENSIONS

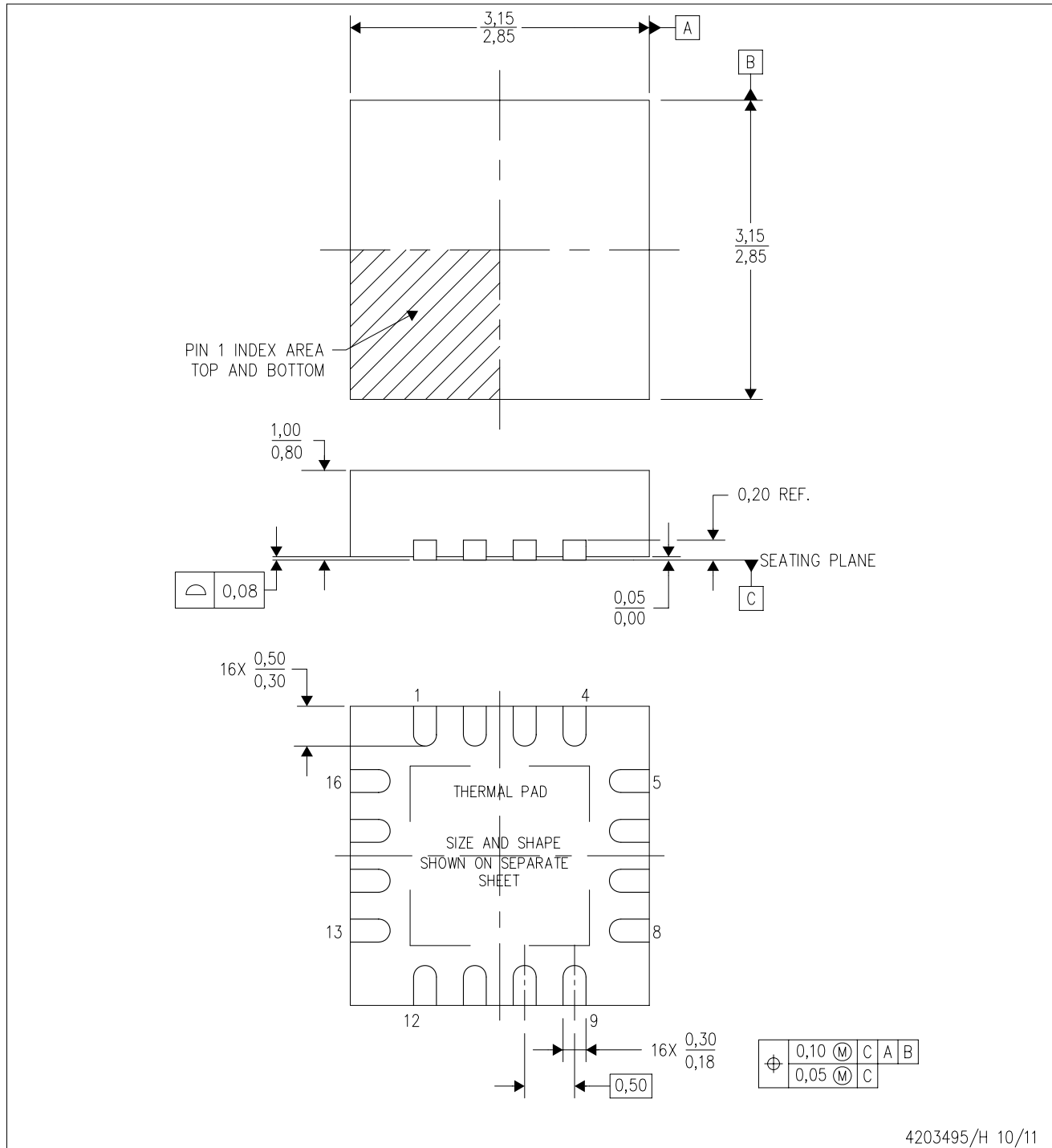


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDCLVD1204RGTR	QFN	RGT	16	3000	338.1	338.1	20.6
CDCLVD1204RGTT	QFN	RGT	16	250	210.0	185.0	35.0

RGT (S-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD



4203495/H 10/11

- NOTES:
- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 - B. This drawing is subject to change without notice.
 - C. Quad Flatpack, No-leads (QFN) package configuration.
 - D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
 - E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
 - F. Falls within JEDEC MO-220.

THERMAL PAD MECHANICAL DATA

RGT (S-PVQFN-N16)

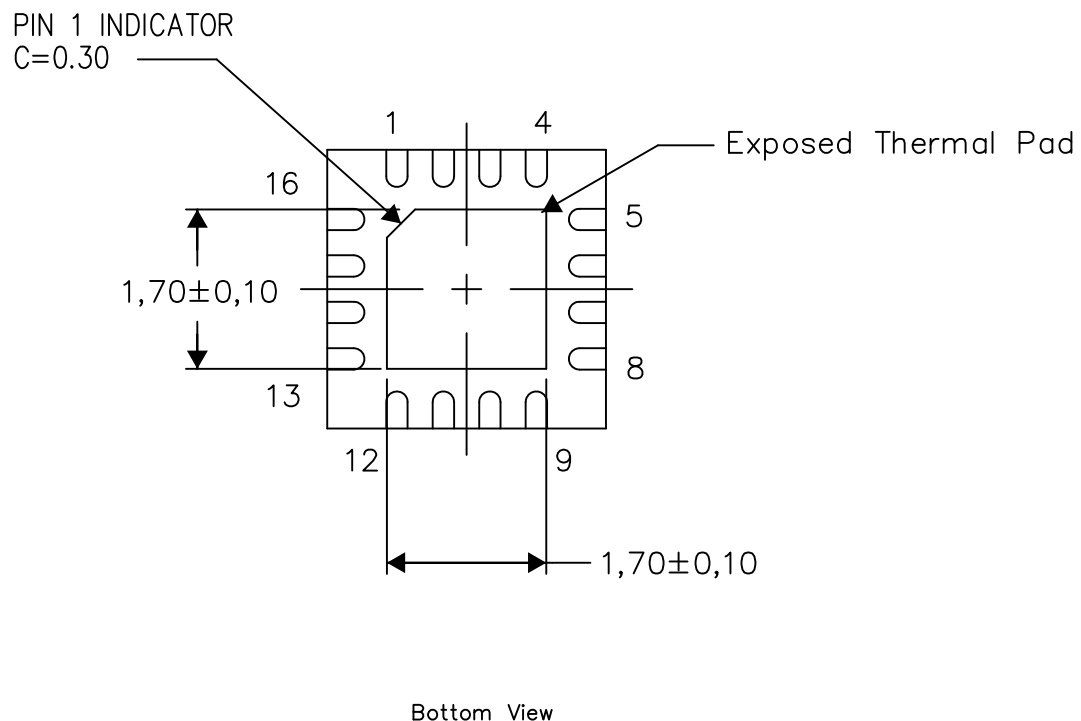
PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



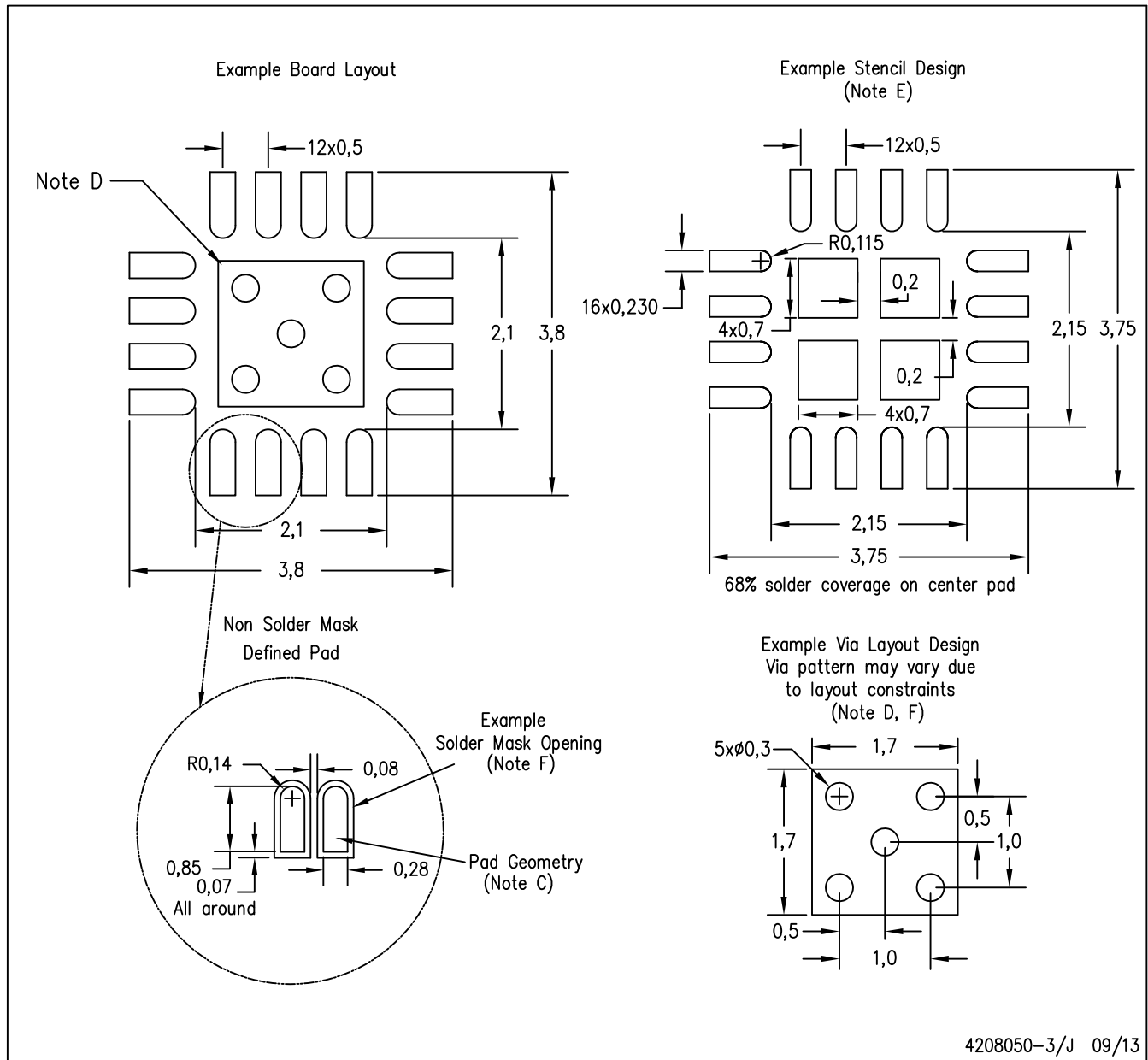
Exposed Thermal Pad Dimensions

4206349-4/U 09/13

NOTE: All linear dimensions are in millimeters

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- NOTES:
- All linear dimensions are in millimeters.
 - This drawing is subject to change without notice.
 - Publication IPC-7351 is recommended for alternate designs.
 - This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <<http://www.ti.com>>.
 - Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
 - Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.

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